## Notice of References Cited Application/Control No. 10/786,032 Examiner Elmira Mehrmanesh Applicant(s)/Patent Under Reexamination IIDA, HIROSHI Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0006552	01-2004	Kakigi, Nobuyoshi	707/1
*	В	US-6,021,444	02-2000	Fukasawa, Toshihiko	719/313
*	C	US-2002/0184405	12-2002	Omori et al.	709/318
*	D	US-2002/0149799	10-2002	Hayashi, Koji	358/406
*	E	US-6,021,444	02-2000	Fukasawa, Toshihiko	719/313
*	F	US-6,088,737	07-2000	Yano et al.	709/235
*	G	US-6,564,245	05-2003	Fukasawa et al.	709/205
*	Н	US-2006/0136707	06-2006	Fukasawa, Hidefumi	713/002
*	1	US-2005/0206939	09-2005	Tsutsumi et al.	358/001.13
*	J	US-2005/0213116	09-2005	Uejo, Hiroyoshi	358/001.1
*	К	US-2006/0059253	03-2006	Goodman et al.	709/223
*	L	US-7,020,697	03-2006	Goodman et al.	709/223
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0			.,		
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	٧	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.